Nuclear Instruments and Methods in Physics Research B 89 (1994) 451–459
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NIM B
Beam Interactions with Materials & Atoms

Author index

Abs, M., see Jongen, Y. 89 (1994) 60
Adamczewski, J., see Meijer, J. 89 (1994) 229
Aguer, P., see Bogaert, G. 89 (1994) 8
Amdidouche, Y., M. Bourgeois, J.L. Collier and T.R. Sherwood, Secondary electron emission factors from metals bombarded with highly-charged, laser-produced tantalum ions 89 (1994) 424
Andersen, H.H., see Johansen, A. 89 (1994) 178
Angert, N., see Neu, K. 89 (1994) 379
Angulo, C., see Bogaert, G. 89 (1994) 8
Annegarn, H.J., see Mesjasz-Przybyłowicz, J. 89 (1994) 208
Anthony, J.M., see McDaniel, F.D. 89 (1994) 242
Arai, E., A. Zounek, N. Sekino and K. Saito, Analysis of boron-doped amorphous silicon by means of a heavy-ion time-of-flight ERD spectrometer 89 (1994) 149
Armour, D.G., Ion beam deposition 89 (1994) 325
Arndt, P., N. Golovanivski, H. Homeyer and M. Martin, BECRIS – a 5 GHz ECR source for a CN Van de Graaff 89 (1994) 14
Arrale, A.M., Z.Y. Zhao, J.F. Kirchhoff, D.K. Marble, D.L. Weathers, F.D. McDaniel and S. Matteson, Model of the contamination effect in ion-induced electron emission 89 (1994) 437
Asher, J., MeV ion processing applications for industry 89 (1994) 315
Assmann, W., H. Huber, Ch. Steinhausen, M. Dobler, H. Glückler and A. Weidinger, Elastic recoil detection analysis with heavy ions 89 (1994) 131
Athanasou, N.A., see Grime, G.W. 89 (1994) 145
Aumkaew, S., see Suwannakachorn, D. 89 (1994) 354
Auslender, V.L., ILU-type electron accelerators for industrial technologies 89 (1994) 46

Bachmann, T., S. Schippel, E. Wendler, W. Wesch, U. Richter and W. Witthuhn, Comparison of MeV-implanted GaAs and InP 89 (1994) 168
Balkwill, K., see Mesjasz-Przybyłowicz, J. 89 (1994) 208
Bange, K., see Wagner, W. 89 (1994) 104
Bardos, R.A., see Cholewa, M. 89 (1994) 157
Barranco, F., see Respaldiza, M.A. 89 (1994) 109
Baumann, H., see Kessler, Th. 89 (1994) 140
Baumann, H., see Markwitz, A. 89 (1994) 362
Baumann, H., see Neu, K. 89 (1994) 379
Behringer, U., see Brunner, S. 89 (1994) 373
Benenson, R.E., see Chen, H. 89 (1994) 401
Bernard, M., see Travier, C. 89 (1994) 27
Berset, J.M., see Prazeres, R. 89 (1994) 54
Bethge, K., see Schenkel, Th. 89 (1994) 79
Bethge, K., see Hebert, H. 89 (1994) 95
Bethge, K., see Kessler, Th. 89 (1994) 140
Bethge, K., see Ditrói, F. 89 (1994) 164
Bethge, K., see Meyer, J.D. 89 (1994) 186
Bethge, K., see Markwitz, A. 89 (1994) 362
Bethge, K., see Neu, K. 89 (1994) 379
Bethge, K., see Luc, J. 89 (1994) 447
Bogaert, G., R. Meunier, D. Ledu, C. Angulo, W.H. Schulte, P. Aguer, A. Coc, A. Lefebvre, F. de Oliveira, J.P. Thibaud, T. Paradellis, E. Kossionides, S. Harissopulos and G. Galios, A 250 kV high current ion accelerator for applications in nuclear astrophysics 89 (1994) 8
Bogdanović, I., see Bogovac, M. 89 (1994) 219
Bogovac, M., I. Bogdanović, S. Fazinić, M. Jakšić, L. Kukec and W. Wilhelm, Data acquisition and scan control system for nuclear microprobe and other multiparameter experiments 89 (1994) 219

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Bolse, W., see Lieb, K.-P. . . . 89 (1994) 277
Bolse, W., see Shi, F. . . . 89 (1994) 332
Bolse, W., see Shi, F. . . . 89 (1994) 382
Boonyawan, D., see Suwannakachorn, D. . . . 89 (1994) 354
Bouchier, D., G. Sené, M.A. Djouadi and P. Möller, Effect of noble gas ions on the synthesis of c-BN by ion beam assisted deposition . . . 89 (1994) 369
Bourgeois, M., see Amdidouche, Y. . . . 89 (1994) 424
Braye, F., see Weber, G. . . . 89 (1994) 200
Broniatowski, A., Low temperature bolometer detectors in ion beam analysis . . . 89 (1994) 394
Bruhn, F., see Meijer, J. . . . 89 (1994) 229
Brunner, S., D.M. Rück, W.F.X. Frank, F. Linke, A. Schösser and U. Behringer, Waveguiding structures in polymers by ion implantation . . . 89 (1994) 373
Bukow, H.H., see Meijer, J. . . . 89 (1994) 229
Bukow, H.H., see Stephan, A. . . . 89 (1994) 420
Büttig, H., see Einfeld, D. . . . 89 (1994) 74

Capdevila, J.M., see Jongen, Y. . . . 89 (1994) 60
Carstanjen, H.D., see Kruse, O. . . . 89 (1994) 191
Ceccato, D., see Valković, O. . . . 89 (1994) 233
Chaput, R., see Prazeres, R. . . . 89 (1994) 54
Chen, H., D.F.R. Mildner, R.G. Downing, R.E. Benenson, Q.F. Xiao and V.A. Sharov, Neutron focusing using capillary optics . . . 89 (1994) 401
Cholewa, M., A. Saint, S. Prawer, J.S. Laird, G.J.F. Legge, R.A. Bardos, G.F. Moorhead, G.N. Taylor, S.-A. Stuart and J. Howard, High resolution techniques using scanning proton microprobe (SPM) . . . 89 (1994) 157
Cluzeau, S. and P. Le Tourneur, Stationary DIANE Equipment Description and performance of the thermal neutron source . . . 89 (1994) 428
Cluzeau, S., J. Huet and P. Le Tourneur, DIANE stationary neutron radiography system image quality and industrial applications . . . 89 (1994) 432
Coc, A., see Bogaert, G. . . . 89 (1994) 8
Collier, J.L., see Amdidouche, Y. . . . 89 (1994) 424
Constantinescu, B., E.A. Ivanov, G. Pascovici, L. Popa-Simil and P.M. Racolta, Thin layer activation techniques at the U-120 cyclotron of Bucharest . . . 89 (1994) 83
Conti, M., see Giorginis, G. . . . 89 (1994) 100
Criddle, A., see Tamana, H. . . . 89 (1994) 213

Dam, B., see van Kan, J.A. . . . 89 (1994) 204
Daniel, J., see Kraus, M. . . . 89 (1994) 307
Dawson, M., see Grime, G.W. . . . 89 (1994) 223
Defrise, D., see Jongen, Y. . . . 89 (1994) 60
Dehen, J., H. Deitinghoff, H. Klein, M. Sarstedt, A. Schempp and R. Thomae, Design study of an energy-variable RF-accelerator for ion implantation . . . 89 (1994) 49
Deitinghoff, H., see Dehen, J. . . . 89 (1994) 49
De Oliveira, F., see Bogaert, G. . . . 89 (1994) 8
De Voigt, M.J.A., see van IJzendoorn, L.J. . . . 89 (1994) 114
Dienel, S., see Einfeld, D. . . . 89 (1994) 74
Ditrói, F., J.D. Meyer, R. Michelmann, D. Kislat and K. Bethge, Investigation of silicon width (p, p′) resonance scattering in ⟨110⟩ channeling direction . . . 89 (1994) 164
Ditrói, F., see Meyer, J.D. . . . 89 (1994) 186
Djouadi, M.A., see Bouchier, D. . . . 89 (1994) 369
Döbeli, M., A. Lombao, D. Vetterli and M. Suter, Thin layer analysis with heavy ion RBS . . . 89 (1994) 174
Dobler, M., see Assmann, W. . . . 89 (1994) 131
Downing, R.G., see Chen, H. . . . 89 (1994) 401
Drwiega, M., see Rajchel, B. . . . 89 (1994) 342
Dufresne, P., see Travier, C. . . . 89 (1994) 27
Duggan, J.L., see Luc, J. . . . 89 (1994) 447
D'yachenko, P.P., see Seregina, E.A. . . . 89 (1994) 412

Einfeld, D., H. Büttig, S. Dienel, W. Gläser, Th. Goetz, H. Guratzsch, B. Hartmann, D. Janssen, H. Krug, J. Linnemann, W. Matz, J.B. Murphy, W. Neumann, W. Oehme, M. Picard, M. Plesko, D. Pröhl, R. Schlenk, D. Tomassini and H. Tyrroff, The synchrotron light source ROSY . . . 89 (1994) 74

Elliman, R.G., see Ridgway, M.C. 89 (1994) 290
Ellingboe, S.L., see Ridgway, M.C. 89 (1994) 290
Ensinger, W., see Müller, H.R. 89 (1994) 357
Erlandsson, B., see Stenström, K. 89 (1994) 256
Erlandsson, B., see Wiebert, A. 89 (1994) 259

Fang, R., see Strasser, A. 89 (1994) 65
Fazinić, S., see Bogovac, M. 89 (1994) 219
Forster, J.S., R.L. Tapping, T. Laursen and J.R. Leslie, The role of stress in deuterium ingress into thin foils of Zr and Zr–2.5wt%Nb 89 (1994) 153
Frank, W.F.X., see Brunner, S. 89 (1994) 373
Frech, G., see Müller, H.R. 89 (1994) 357
Friedrich, K., see Kessler, Th. 89 (1994) 140

Galassini, S., see Valković, O. 89 (1994) 233
Galios, G., see Bogaert, G. 89 (1994) 8
Garwan, M.A., M.-J. Nadeau, X.-L. Zhao and A.E. Litherland, Hydride ambiguities in the accelerator mass spectrometry (AMS) of heavy elements 89 (1994) 250
Genin, F., see Jongen, Y. 89 (1994) 60
Giorginis, G., P. Misaelides and M. Conti, Characterization of boron nitride thin films using (α, p) nuclear reactions 89 (1994) 100
Gläser, W., see Einfeld, D. 89 (1994) 74
Glotin, F., see Prazeres, R. 89 (1994) 54
Glückler, H., see Assmann, W. 89 (1994) 131
Goetz, Th., see Einfeld, D. 89 (1994) 74
Golovanivski, N., see Arndt, P. 89 (1994) 14
Gómez-Tubío, B.M., see Respaldiza, M.A. 89 (1994) 109
Grannan, E.C., see McDaniel, F.D. 89 (1994) 242
Green, J.P., see Suwannakachorn, D. 89 (1994) 354
Grill, W., see Markwitz, A. 89 (1994) 362
Grime, G., see Tamana, H. 89 (1994) 213
Grime, G.W., J.T. Triffitt, M.C. Williamson and N.A. Athanasou, Nuclear microbeam analysis of wear particles in tissue surrounding failed hip joint implants 89 (1994) 145
Grime, G.W. and M. Dawson, A PC-based data acquisition package for nuclear microbeam systems 89 (1994) 223
Guratzsch, H., see Einfeld, D. 89 (1994) 74

Harissopulos, S., see Bogaert, G. 89 (1994) 8
Hartmann, B., see Einfeld, D. 89 (1994) 74
Hattori, T., see Okamura, M. 89 (1994) 38
Hattori, T., see Oguri, Y. 89 (1994) 42
Hebert, H., Th. Schenkel, J.D. Meyer, R.W. Michelmann and K. Bethge, Localization and mobility of oxygen in monocrystalline GaAs by channeling-NRA 89 (1994) 95
Hebert, H., see Schenkel, Th. 89 (1994) 79
Heinig, K.-H., see Reiss, S. 89 (1994) 337
Hellborg, R., see Stenström, K. 89 (1994) 256
Hellborg, R., see Wiebert, A. 89 (1994) 259
Hemment, P.L.F., see Sealy, B.J. 89 (1994) 298
Höfert, M., see Stephan, A. 89 (1994) 420
Holmes, A.J.T., see Proudfoot, G. 89 (1994) 1
Holzapfel, B., see Kraus, M. 89 (1994) 307
Homeyer, H., see Arndt, P. 89 (1994) 14
Howard, J., see Cholewa, M. 89 (1994) 157
Huber, H., see Assmann, W. 89 (1994) 131
Huet, J., see Cluzeau, S. 89 (1994) 432

Irigaray, J.L., see Weber, G. 89 (1994) 200
Ishii, Y., see Saitoh, Y. 89 (1994) 23
Ito, T., see Okamura, M. 89 (1994) 38
Ivanov, E.A., see Constantinescu, B. 89 (1994) 83
Iwamoto, E., see Saitoh, Y. 89 (1994) 23

Jakšić, M., see Bogovac, M. 89 (1994) 219
Janssen, D., see Einfeld, D. 89 (1994) 74
Jaroszynski, D.A., see Prazeres, R. 89 (1994) 54
Johansen, A., E. Johnson, H.H. Andersen, L. Sarholt-Kristensen and M. Olsen, Channeling and TEM investigation of nanosized thallium inclusions in aluminium 89 (1994) 178
Johnson, E., see Johansen, A. 89 (1994) 178
Jongen, Y., M. Abs, J.M. Capdevila, D. Defrise, F. Genin and A. NGuyen, The Rhodotron, a new high-energy, high-power, CW electron accelerator 89 (1994) 60

Kalinin, V.V., see Seregina, E.A. 89 (1994) 412
Kamiya, T., see Saitoh, Y. 89 (1994) 23
Keinonen, J., see Persson, L. 89 (1994) 346
Kessler, Th., H. Baumann, J. Reinmann, K. Friedrich, R. Omet and K. Bethge, Analysis and characterization of a new magneto-optic display material 89 (1994) 140
Kim, Y.D., see McDaniel, F.D. 89 (1994) 242
Kirchhoff, J.F., see McDaniel, F.D. 89 (1994) 242
Kirchhoff, J.F., see Arrale, A.M. 89 (1994) 437
Kislat, D., see Ditrói, F. 89 (1994) 164
Klein, H., see Sarstedt, M. 89 (1994) 17
Klein, H., see Dehen, J. 89 (1994) 49
Knop, A., see Markwitz, A. 89 (1994) 362
Knox, J., see Persson, L. 89 (1994) 346
Kögler, R., J. von Borany, D. Panknin and W. Skorupa, Electrical effects of residual defects in Si after high energy implantation of Ge^+ ions and annealing 89 (1994) 350
Kossionides, E., see Bogaert, G. 89 (1994) 8
Kraus, M., G. Kreiselmeyer, J. Daniel, M. Leghissa, G. Saemann-Ischenko, B. Holzapfel, P. Kummeth, R. Scholz and L.Ya. Vinnikov, Tailored defects in HTSC – What can we learn from swift heavy ion irradiation? 89 (1994) 307
Kreiselmeyer, G., see Kraus, M. 89 (1994) 307
Krimmel, E.F., see Markwitz, A. 89 (1994) 362
Krug, H., see Einfeld, D. 89 (1994) 74
Kruse, O. and H.D. Carstanjen, High depth resolution ERDA of H and D by means of an electrostatic spectrometer 89 (1994) 191
Kukec, L., see Bogovac, M. 89 (1994) 219
Kummeth, P., see Kraus, M. 89 (1994) 307
Kuntz, F., see Strasser, A. 89 (1994) 65

Laird, J.S., see Cholewa, M. 89 (1994) 157
Laursen, T., see Forster, J.S. 89 (1994) 153
Lebrun, J.L., K. Bethge and J.L. Duggan, Applied research and technology with accelerators – State of the art, 1993 . . . . . 89 (1994) 447
Ledu, D., see Bogaert, G. 89 (1994) 8
Lefebvre, A., see Bogaert, G. 89 (1994) 8
Legge, G.J.F., see Cholewa, M. 89 (1994) 157
Leghissa, M., see Kraus, M. 89 (1994) 307
Lehnert, U., K. Merla and G. Zschornack, A high resolution crystal diffraction spectrometer for X-ray analysis 89 (1994) 238
Leslie, J.R., see Forster, J.S. 89 (1994) 153
Le Tourneur, P., see Cluzeau, S. 89 (1994) 428
Le Tourneur, P., see Cluzeau, S. 89 (1994) 432
Lieb, K.-P., W. Bolse and M. Uhrmacher, Ion beam mixing in metal/metal and nitride/metal layers – new perspectives 89 (1994) 277
Lieb, K.P., see Shi, F. 89 (1994) 332
Lieb, K.P., see Shi, F. 89 (1994) 382
Linke, F., see Brunner, S. 89 (1994) 373
Linnemann, J., see Einfeld, D. 89 (1994) 74
Lipińska, E., see Rajchel, B. 89 (1994) 342
Litherland, A.E., see Garwan, M.A. 89 (1994) 250
Lombao, A., see Döbeli, M. 89 (1994) 174

Maaser, A., see Sarstedt, M. 89 (1994) 17
Malmqvist, K.G., see Persson, L. 89 (1994) 346
Marble, D.K., see McDaniel, F.D. 89 (1994) 242
Marble, D.K., see Arrale, A.M. 89 (1994) 437
Marin, P.C., Synchrotron radiation stimulated gas desorption from metals 89 (1994) 69
Markwitz, A., H. Baumann, W. Grill, A. Knop, E.F. Krimmel and K. Bethge, Investigations of ultrathin silicon nitride layers produced by low-energy ion implantation and EB-RTA 89 (1994) 362
Martin, M., see Arndt, P. 89 (1994) 14
Matteson, S., see McDaniel, F.D. 89 (1994) 242
Matteson, S., see Arrale, A.M. 89 (1994) 437
Matz, W., see Einfeld, D. 89 (1994) 74
Maximov, I., see Persson, L. 89 (1994) 346
McAdams, R., see Proudfoot, G. 89 (1994) 1
McDaniel, F.D., J.M. Anthony, J.F. Kirchhoff, D.K. Marble, Y.D. Kim, S.N. Renfrow, E.C. Grannan, E.R. Reznik, G. Vizkelethy and S. Matteson, Impurity determination in electronic materials by accelerator mass spectrometry 89 (1994) 242
McDaniel, F.D., see Arrale, A.M. 89 (1994) 437
Meijer, J., A. Stephan, J. Adamczewski, H.H. Bukow, C. Rolfs, T. Pickart, F. Bruhn and J. Veizer, PIXE microprobe for geoscience applications 89 (1994) 229
Meijer, J., see Stephan, A. 89 (1994) 420
Menapace, E., see Valković, O. 89 (1994) 233
Merla, K., see Lehnert, U. 89 (1994) 238
Mesjasz-Przybyłowicz, J., K. Balkwill, W.J. Przybyłowicz and H.J. Annegarn, Proton microprobe and X-ray fluorescence investigations of nickel distribution in serpentine flora from South Africa 89 (1994) 208
Meunier, R., see Bogaert, G. 89 (1994) 8
Meyer, J.D., R.W. Michelmann, F. Ditrói and K. Bethge, Investigation of the electronic energy loss of light ions for materials analysis 89 (1994) 186
Meyer, J.D., see Schenkel, Th. 89 (1994) 79
Meyer, J.D., see Hebert, H. 89 (1994) 95
Meyer, J.D., see Ditrói, F. 89 (1994) 164
Michaud, G., see Travier, C. 89 (1994) 27
Michelmann, R., see Ditrói, F. 89 (1994) 164
Michelmann, R.W., see Schenkel, Th. 89 (1994) 79
Michelmann, R.W., see Hebert, H. 89 (1994) 95
Michelmann, R.W., see Meyer, J.D. 89 (1994) 186
Milazzo, M., see Silari, M. 89 (1994) 33
Mildner, D.F.R., see Chen, H. 89 (1994) 401
Misaelides, P., see Giorginis, G. 89 (1994) 100
Miura, T., see Okamura, M. 89 (1994) 38
Mizuhashi, K., see Saitoh, Y. 89 (1994) 23
Möller, P., see Bouchier, D. 89 (1994) 369
Möller, W., Computer simulation of ion-beam assisted film growth 89 (1994) 322
Moorhead, G.F., see Cholewa, M. 89 (1994) 157
Moschini, G., see Valković, O. 89 (1994) 233
Müller, H.R., W. Ensinger, G. Frech and G.K. Wolf, A new approach to ion beam modification of powders . . 89 (1994) 357
Müller, J., see Sarstedt, M. 89 (1994) 17
Murphy, J.B., see Einfeld, D. 89 (1994) 74

Nadeau, M.-J., see Garwan, M.A. 89 (1994) 250
Nassisi, V., Ions and electrons generated by an UV excimer laser 89 (1994) 443
Neu, K., H. Baumann, N. Angert, D. Rück and K. Bethge, Gettering of hydrogen in titanium caused by nitrogen implantation 89 (1994) 379
Neumann, W., see Einfeld, D. 89 (1994) 74
Nguyen, A., see Jongen, Y. 89 (1994) 60
Nguyen, A., see Umiastowski, K. 89 (1994) 416
Nielsen, T., see Stenström, K. 89 (1994) 256
Niemantsverdriet, J.W., see van IJzendoorn, L.J. 89 (1994) 114

Oehme, W., see Einfeld, D. 89 (1994) 74
Oguri, Y., G. Wu and T. Hattori, Effects of 3D image charge force on the motion of off-centered beams in an RFQ 89 (1994) 42

Oguri, Y., see Okamura, M. 89 (1994) 38
Ohkoshi, K., see Saitoh, Y. 89 (1994) 23
Okada, M., see Okamura, M. 89 (1994) 38
Okamura, M., Y. Oguri, K. Sasa, T. Ito, M. Okada, T. Hattori, O. Takeda, K. Satoh, T. Miura, Y. Tanabe and N. Tokuda, Design and construction of heavy ion RFQ linac with effective acceleration structure 89 (1994) 38
Olsen, M., see Johansen, A. 89 (1994) 178
Omeich, M., see Travier, C. 89 (1994) 27
Omet, R., see Kessler, Th. 89 (1994) 140
Ortega, J.M., see Prazeres, R. 89 (1994) 54
Oudadesse, H., see Weber, G. 89 (1994) 200

Panknin, D., see Kögler, R. 89 (1994) 350
Paradellis, T., see Bogaert, G. 89 (1994) 8
Pascovici, G., see Constantinescu, B. 89 (1994) 83
Persson, L., H.J. Whitlow, J. Keinonen, P. Torri, I. Maximov, L. Samuelsson, J. Knox and K.G. Malmqvist, $^{1}H(^{15}N,\alpha\gamma)^{12}C$ nuclear resonance broadening measurements of hydrogen incorporation during plasma etching of GaAs and $Ga_xIn_{(1-x)}As$ quantum wells 89 (1994) 346
Picard, M., see Einfeld, D. 89 (1994) 74
Pickart, T., see Meijer, J. 89 (1994) 229
Plesko, M., see Einfeld, D. 89 (1994) 74
Popa-Simil, L., see Constantinescu, B. 89 (1994) 83
Prawer, S., see Cholewa, M. 89 (1994) 157
Prazeres, R., J.M. Berset, R. Chaput, F. Glotin, D.A. Jaroszynski and J.M. Ortega, CLIO, an infrared free electron laser facility 89 (1994) 54
Pröhl, D., see Einfeld, D. 89 (1994) 74
Proudfoot, G., R. McAdams and A.J.T. Holmes, A new design of a compact high current ion accelerator . . . 89 (1994) 1
Przybyłowicz, W.J., see Mesjasz-Przybyłowicz, J. 89 (1994) 208

Racolta, P.M., see Constantinescu, B. 89 (1994) 83
Raiser, D., I. Rossini and J.C. Sens, Diffusion parameters at the Pt–Co interface 89 (1994) 183
Rajchel, B., M. Drwiega, E. Lipińska and M. Wierba, Adaptation of the 70 kV INP ion implanter to the IBAD technique 89 (1994) 342
Rauch, F., see Wagner, W. 89 (1994) 104
Rector, J.H., see van Kan, J.A. 89 (1994) 204
Reinmann, J., see Kessler, Th. 89 (1994) 140
Reiss, S., R. Weber, K.-H. Heinig and W. Skorupa, Experimental study and modeling of structure formation in buried layers at ion beam synthesis 89 (1994) 337
Renfrow, S.N., see McDaniel, F.D. 89 (1994) 242
Respaldiza, M.A., B.M. Gómez-Tubío, A. Sánchez del Junco, F. Barranco and C. Sáiz-Jiménez, Non-destructive analysis of archaeological bronzes by nuclear techniques 89 (1994) 109
Reznik, E.R., see McDaniel, F.D. 89 (1994) 242
Richter, U., see Bachmann, T. 89 (1994) 168
Ridgway, M.C., S.L. Ellingboe, R.G. Elliman and J.S. Williams, High-energy ion implantation for electrical isolation of microelectronic devices 89 (1994) 290
Robaye, G., see Weber, G. 89 (1994) 200
Roch, M., see Travier, C. 89 (1994) 27
Rodier, J., see Travier, C. 89 (1994) 27
Rolfs, C., see Meijer, J. 89 (1994) 229
Rolfs, C., see Stephan, A. 89 (1994) 420
Rossini, I., see Raiser, D. 89 (1994) 183
Rück, D., see Neu, K. 89 (1994) 379
Rück, D.M., see Brunner, S. 89 (1994) 373

Saemann-Ischenko, G., see Kraus, M. 89 (1994) 307
Saint, A., see Cholewa, M. 89 (1994) 157
Saito, K., see Arai, E. 89 (1994) 149
Saitoh, Y., S. Tajima, I. Takada, K. Mizuhashi, S. Uno, K. Ohkoshi, Y. Ishii, T. Kamiya, K. Yotumoto, R. Tanaka and E. Iwamoto, TIARA electrostatic accelerators for multiple ion beam application 89 (1994) 23
Sáiz-Jiménez, C., see Respaldiza, M.A. 89 (1994) 109
Samuelsson, L., see Persson, L. 89 (1994) 346
Sánchez del Junco, A., see Respaldiza, M.A. 89 (1994) 109

Sarholt-Kristensen, L., see Johansen, A. 89 (1994) 178
Sarstedt, M., R. Thomae, H. Klein, A. Maaser, J. Müller, B. Seiler and M. Weber, Beam profile and emittance measurements for ion implantation 89 (1994) 17
Sarstedt, M., see Dehen, J. 89 (1994) 49
Sasa, K., see Okamura, M. 89 (1994) 38
Satoh, K., see Okamura, M. 89 (1994) 38
Schempp, A., see Dehen, J. 89 (1994) 49
Schenkel, Th., H. Hebert, J.D. Meyer, R.W. Michelmann and K. Bethge, Channeling charged particle activation analysis of light impurities at trace levels in GaAs 89 (1994) 79
Schenkel, Th., see Hebert, H. 89 (1994) 95
Schippel, S., see Bachmann, T. 89 (1994) 168
Schlenk, R., see Einfeld, D. 89 (1994) 74
Scholz, R., see Kraus, M. 89 (1994) 307
Schösser, A., see Brunner, S. 89 (1994) 373
Schulte, W.H., see Bogaert, G. 89 (1994) 8
Sealy, B.J. and P.L.F. Hemment, Ion beam techniques in microelectronics 89 (1994) 298
Seiler, B., see Sarstedt, M. 89 (1994) 17
Sekino, N., see Arai, E. 89 (1994) 149
Sené, G., see Bouchier, D. 89 (1994) 369
Sens, J.C., see Raiser, D. 89 (1994) 183
Seregina, E.A., P.P. D'yachenko and V.V. Kalinin, Application of accelerator in research of condensed lasants for nuclear pumped lasers 89 (1994) 412
Severens, R.J., see van IJzendoorn, L.J. 89 (1994) 114
Sharov, V.A., see Chen, H. 89 (1994) 401
Sherwood, T.R., see Amdidouche, Y. 89 (1994) 424
Shi, F., W. Bolse and K.P. Lieb, Spike effects in the ion mixing of metallic marker system 89 (1994) 332
Shi, F., W. Bolse, K.P. Lieb and J.-P. Wilbrandt, Ion-beam induced modifications of Sb-Al bilayers 89 (1994) 382
Silari, M. and M. Milazzo, Conceptual design of a compact photon source in the 1–100 keV range 89 (1994) 33
Skog, G., see Stenström, K. 89 (1994) 256
Skog, G., see Wiebert, A. 89 (1994) 259
Skorupa, W., see Reiss, S. 89 (1994) 337
Skorupa, W., see Kögler, R. 89 (1994) 350
Spratt, J., see Tamana, H. 89 (1994) 213
Steinhausen, Ch., see Assmann, W. 89 (1994) 131
Stenström, K., B. Erlandsson, R. Hellborg, A. Wiebert, G. Skog and T. Nielsen, Accelerator mass spectrometry analysis of aroma compound absorption in plastic packaging materials 89 (1994) 256
Stenström, K., see Wiebert, A. 89 (1994) 259
Stephan, A., J. Meijer, M. Höfert, H.H. Bukow and C. Rolfs, A superconducting solenoid as probe forming lens for microprobe applications 89 (1994) 420
Stephan, A., see Meijer, J. 89 (1994) 229
Strasser, A., R. Fang and F. Kuntz, Improvement of electron beam shape control in radiation processing . . . 89 (1994) 65
Stuart, S.-A., see Cholewa, M. 89 (1994) 157
Suter, M., see Döbeli, M. 89 (1994) 174
Suter, M., see Zoppi, U. 89 (1994) 262
Suter, M., see Wagner, M.J.M. 89 (1994) 266
Suwannakachorn, D., D. Boonyawan, J.P. Green, S. Aumkaew, C. Thongleurm, P. Vichaisirimongkol and T. Vilaithong, A heavy ion implanting facility at the Chiang Mai University 89 (1994) 354
Synal, H.-A., see Zoppi, U. 89 (1994) 262
Synal, H.-A., see Wagner, M.J.M. 89 (1994) 266

Tajima, S., see Saitoh, Y. 89 (1994) 23
Takács, S., L. Vasváry and F. Tárkányi, Remeasurement and compilation of excitation function of proton induced reactions on iron for activation techniques 89 (1994) 88
Takada, I., see Saitoh, Y. 89 (1994) 23
Takeda, O., see Okamura, M. 89 (1994) 38
Tamana, H., A. Criddle, G. Grime, D. Vaughan and J. Spratt, Trace elements in platinum group minerals studied using nuclear microscopy 89 (1994) 213
Tanabe, Y., see Okamura, M. 89 (1994) 38
Tanaka, R., see Saitoh, Y. 89 (1994) 23
Tapping, R.L., see Forster, J.S. 89 (1994) 153
Tárkányi, F., see Takács, S. 89 (1994) 88

Taylor, G.N., see Cholewa, M. . . . 89 (1994) 157
Thibaud, J.P., see Bogaert, G. . . . 89 (1994) 8
Thomae, R., see Sarstedt, M. . . . 89 (1994) 17
Thomae, R., see Dehen, J. . . . 89 (1994) 49
Thongleurm, C., see Suwannakachorn, D. . . . 89 (1994) 354
Tokuda, N., see Okamura, M. . . . 89 (1994) 38
Tomassini, D., see Einfeld, D. . . . 89 (1994) 74
Torri, P., see Persson, L. . . . 89 (1994) 346
Townsend, P.D., Ion implanted waveguide lasers in insulators . . . 89 (1994) 270
Travier, C., M. Bernard, P. Dufresne, G. Michaud, M. Omeich, M. Roch and J. Rodier, CANDELA photo-injector high-power tests . . . 89 (1994) 27
Triffitt, J.T., see Grime, G.W. . . . 89 (1994) 145
Tyrroff, H., see Einfeld, D. . . . 89 (1994) 74

Uhrmacher, M., see Lieb, K.-P. . . . 89 (1994) 277
Umiastowski, K. and A. Nguyen, Transition radiation very soft X-ray source . . . 89 (1994) 416
Uno, S., see Saitoh, Y. . . . 89 (1994) 23

Valković, O., D. Ceccato, G. Moschini, S. Galassini and E. Menapace, Reference materials for PIXE analysis of aerosols . . . 89 (1994) 233
Van Dijk, P.W.L., see van IJzendoorn, L.J. . . . 89 (1994) 114
Van IJzendoorn, L.J., J.W. Niemantsverdriet, R.J. Severens, P.W.L. van Dijk and M.J.A. de Voigt, Applications of cyclotron based ion scattering . . . 89 (1994) 114
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Vasváry, L., see Takács, S. . . . 89 (1994) 88
Vaughan, D., see Tamana, H. . . . 89 (1994) 213
Veizer, J., see Meijer, J. . . . 89 (1994) 229
Vetterli, D., see Döbeli, M. . . . 89 (1994) 174
Vichaisirimongkol, P., see Suwannakachorn, D. . . . 89 (1994) 354
Vilaithong, T., see Suwannakachorn, D. . . . 89 (1994) 354
Vinnikov, L.Ya., see Kraus, M. . . . 89 (1994) 307
Vis, R.D., see van Kan, J.A. . . . 89 (1994) 204
Vizkelethy, G., Computer simulation of ion beam methods in analysis of thin films . . . 89 (1994) 122
Vizkelethy, G., see McDaniel, F.D. . . . 89 (1994) 242
Von Borany, J., see Kögler, R. . . . 89 (1994) 350
Vourvopoulos, G., Accelerator based techniques for contraband detection . . . 89 (1994) 388

Wagner, M.J.M., H.-A. Synal and M. Suter, Isobar discrimination in accelerator mass spectrometry by detecting characteristic projectile X-rays . . . 89 (1994) 266
Wagner, W., F. Rauch and K. Bange, Stoichiometry of NiO_xH_y films determined by ion-beam analysis . . . 89 (1994) 104
Weathers, D.L., see Arrale, A.M. . . . 89 (1994) 437
Weber, G., G. Robaye, F. Braye, H. Oudadesse and J.L. Irigaray, PIXE study of the kinetics of biomaterials ossification . . . 89 (1994) 200
Weber, M., see Sarstedt, M. . . . 89 (1994) 17
Weber, R., see Reiss, S. . . . 89 (1994) 337
Weidinger, A., see Assmann, W. . . . 89 (1994) 131
Wendler, E., see Bachmann, T. . . . 89 (1994) 168
Wesch, W., see Bachmann, T. . . . 89 (1994) 168
Whitlow, H.J., see Persson, L. . . . 89 (1994) 346
Wiebert, A., B. Erlandsson, R. Hellborg, K. Stenström and G. Skog, The charge state distributions of carbon beams measured at the Lund Pelletron accelerator . . . 89 (1994) 259
Wiebert, A., see Stenström, K. . . . 89 (1994) 256
Wierba, M., see Rajchel, B. . . . 89 (1994) 342
Wilbrandt, J.-P., see Shi, F. . . . 89 (1994) 382
Wilhelm, W., see Bogovac, M. . . . 89 (1994) 219
Williams, J.S., see Ridgway, M.C. . . . 89 (1994) 290
Williamson, M.C., see Grime, G.W. . . . 89 (1994) 145
Witthuhn, W., see Bachmann, T. . . . 89 (1994) 168
Wolf, G.K., see Müller, H.R. . . . 89 (1994) 357
Wu, G., see Oguri, Y. . . . 89 (1994) 42

Xiao, Q.F., see Chen, H. 89 (1994) 401

Yotumoto, K., see Saitoh, Y. 89 (1994) 23

Zhao, X.-L., see Garwan, M.A. 89 (1994) 250
Zhao, Z.Y., see Arrale, A.M. 89 (1994) 437
Zoppi, U., M. Suter and H.-A. Synal, Isobar separation with gas ionization counters in accelerator mass spectrometry 89 (1994) 262
Zounek, A., see Arai, E. 89 (1994) 149
Zschornack, G., see Lehnert, U. 89 (1994) 238